

NDT3055L

N-Channel Logic Level Enhancement Mode Field Effect Transistor

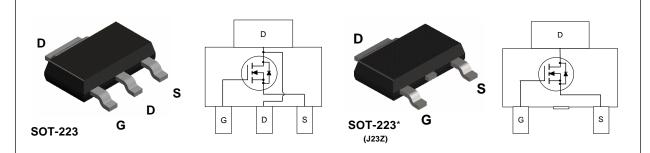
General Description

These logic level N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance, and withstand high energy pulse in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as DC motor control and DC/DC conversion where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- Low drive requirements allowing operation directly from logic drivers. V_{GS(TH)} < 2V.
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.





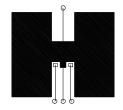
Absolute Maximum Ratings $T_A = 25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	NDT3055L	Units
V _{DSS}	Drain-Source Voltage	60	V
V_{GSS}	Gate-Source Voltage - Continuous	±20	V
l _D	Maximum Drain Current - Continuous (Note 1a)	4	А
	- Pulsed	25	
P_{D}	Maximum Power Dissipation (Note 1a)	3	W
	(Note 1b)	1.3	
	(Note 1c)	1.1	
Γ_{J} , T_{STG}	Operating and Storage Temperature Range	-65 to 150	℃
THERMA	L CHARACTERISTICS		
R _{eJA}	Thermal Resistance, Junction-to-Ambient (Note 1a)	42	°C/W
₹ _{euc}	Thermal Resistance, Junction-to-Case (Note 1)	12	°C/W
Order op	tion J23Z for cropped center drain lead.		

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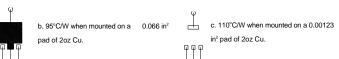
Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHAR	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		60			V
Δ BV _{DSS} / Δ T _J	Breakdown Voltage Temp. Coefficient	I _D = 250 μA, Referenced to 25 °C			55		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$ $T_J = 125^{\circ}\text{C}$			1	μA	
			T _J =125°C			50	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
	ACTERISTICS (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1	1.6	2	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	$I_D = 250 \mu\text{A}$, Referenced to	25 °C		-4		mV /°C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 4 \text{ A}$		0.07	0.1	Ω	
,			T _J =125°C		0.125	0.18	
		$V_{GS} = 4.5 \text{ V}, I_D = 3.7 \text{ A}$			0.103	0.12	
D(ON)	On-State Drain Current	$V_{GS} = 5$, $V_{DS} = 10 \text{ V}$		10			Α
g _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 4 \text{ A}$			7		S
DYNAMIC	CHARACTERISTICS	<u> </u>			•		•
C _{iss}	Input Capacitance	$V_{DS} = 25, \ V_{GS} = 0 \text{ V},$ f = 1.0 MHz			345		pF
Coss	Output Capacitance				110		pF
C _{rss}	Reverse Transfer Capacitance				30		pF
WITCHIN	G CHARACTERISTICS (Note 2)						
D(on)	Tum - On Delay Time	$V_{DD} = 25, I_{D} = 1 A,$ $V_{GS} = 10 V, R_{GEN} = 6 \Omega$			5	20	ns
r	Turn - On Rise Time				7.5	20	ns
D(off)	Turn - Off Delay Time				20	50	ns
f	Turn - Off Fall Time				7	20	ns
Q_g	Total Gate Charge	$V_{DS} = 40 \text{ V}, I_{D} = 4 \text{ A},$ $V_{GS} = 10 \text{ V}$			13	20	nC
Q_{gs}	Gate-Source Charge				1.7		nC
Q_{gd}	Gate-Drain Charge				3.2		nC
DRAIN-SO	URCE DIODE CHARACTERISTICS AND MAX	IMUM RATINGS					
S	Maximum Continuous Drain-Source Diode Forward Current				2.5	Α	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.5 \text{ A}$ (Note	2)		0.8	1.2	V

the drain pins. $\boldsymbol{R}_{\boldsymbol{\theta}^{JC}}$ is 1. R_{gut} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of guaranteed by design while $\boldsymbol{R}_{\theta \text{CA}}$ is determined by the user's board design.



a. 42°C/W when mounted on a 1 in² pad of 2oz Cu.





Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%

Typical Electrical Characteristics

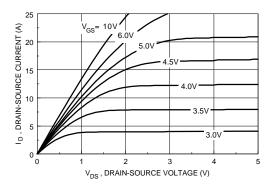


Figure 1. On-Region Characteristics.

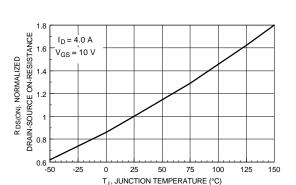


Figure 3. On-Resistance Variation with Temperature.

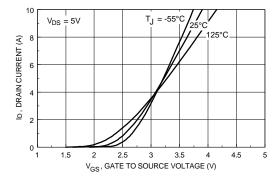


Figure 5. Transfer Characteristics.

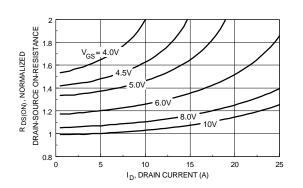


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

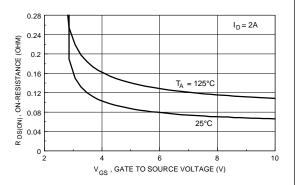


Figure 4. On-Resistance Variation with Gate-to- Source Voltage.

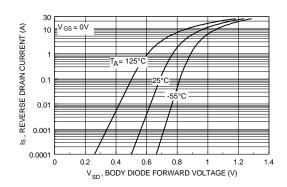


Figure 6. Body Diode Forward Voltage Variation with Current and Temperature.

Typical Electrical Characteristics (continued)

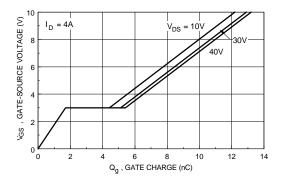


Figure 7. Gate Charge Characteristics.

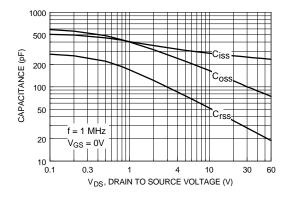


Figure 8. Capacitance Characteristics.

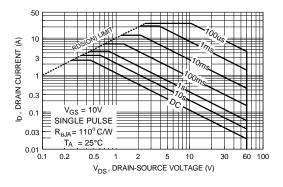


Figure 9. Maximum Safe Operating Area.

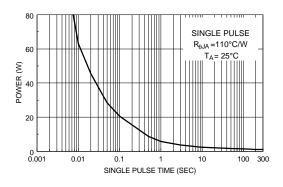


Figure 10. Single Pulse Maximum Power Dissipation.

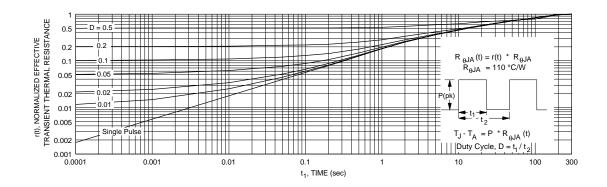


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in note 1c.

Transient thermal response will change depending on the circuit board design.

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